Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/686,636	TANAKA, YONETA	
Examiner	Art Unit .	
Judson H. Jones	2834	

	SEAR	CHED	
Class	Subclass	Date	Examiner
310	12	6/2/2005	JHJ
355	53,72	6/2/2005	ìнл
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IN	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
above	searched	8/18/05	gHf

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
USPTO BRS search search terms: wafer and stage same (piezo or piezoelect\$8) USPAT, PGPUB, EPO, JPO and Derwent	6/4/2005	1HJ
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